Search	Notes	

_	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/731,571	HUFF ET AL.
	Examiner	Art Unit
	Ellen C. Tran	2134

SEARCHED				
Class	Subclass	Date	Examiner	
713	168	3/27/2006	ECT	
380	270	3/27/2006	ECT	
726	3	3/31/2006	ECT	
709	229	3/31/2006	ECT	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
Interferen	ce Search	3/27/2006	ECT	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	3/27/2006	ECT ·
NPL IEEE XPLORE	3/27/2006	ECT
PALM INVENTOR	3/27/2006	ECT
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